

HM514100A Series**HM514100AL Series** Low Power Version**HM514100ASL Series** Super Low Power Version

Preliminary

T-46-23-17

4,194,304-Word x 1-Bit Dynamic Random Access Memory

■ DESCRIPTION

The Hitachi HM514100A is a CMOS dynamic RAM organized 4,194,304 word x 1-bit HM514100A has realized higher density, higher performance and various functions by employing 0.8 μ m CMOS process technology and some new CMOS circuit design technologies. The HM514100A offers Fast Page Mode as a high speed access mode.

Multiplexed address input permits the HM514100A to be packaged in standard 350 mil 20-pin plastic SOJ, standard 300 mil 20-pin plastic SOJ, standard 400 mil 20-pin plastic ZIP, 20-pin plastic TSOP I, 20-pin plastic TSOP I reverse type, 20-pin plastic TSOP II, and 20-pin plastic TSOP II reverse type.

■ FEATURES

- Single 5V ($\pm 10\%$)
- High Speed
 - Access Time 60 ns/70 ns/80 ns/100 ns (max)
- Low Power Dissipation
 - Active Mode 605 mW/550 mW/495 mW/440 mW (max)
 - Standby Mode 11 mW (max)
- Fast Page Mode Capability
- 1,024 Refresh Cycles (16 ms, 128 ms, 256 ms)
- 3 Variations of Refresh
 - RAS Only Refresh
 - CAS Before RAS Refresh
 - Hidden Refresh
- Test Function
- Battery Back Up Operation
 - HM514100AL Series (L-Version)
- Data Retention Operation
 - HM514100ASL Series (SL-Version)

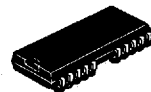
■ ORDERING INFORMATION

Part No.	Access Time	Package
HM514100AJ/ALJ/ASLJ-6	60 ns	350 mil 20-pin Plastic SOJ
HM514100AJ/ALJ/ASLJ-7	70 ns	(CP-20DA)
HM514100AJ/ALJ/ASLJ-8	80 ns	
HM514100AJ/ALJ/ASLJ-10	100 ns	
HM514100AS/ALS/ASLS-6	60 ns	300 mil 20-pin Plastic SOJ
HM514100AS/ALS/ASLS-7	70 ns	(CP-20D)
HM514100AS/ALS/ASLS-8	80 ns	
HM514100AS/ALS/ASLS-10	100 ns	
HM514100AZ/ALZ/ASLZ-6	60 ns	400 mil 20-pin Plastic ZIP
HM514100AZ/ALZ/ASLZ-7	70 ns	(ZP-20)
HM514100AZ/ALZ/ASLZ-8	80 ns	
HM514100AZ/ALZ/ASLZ-10	100 ns	
HM514100AT/ALT/ASLT-6	60 ns	20-pin Plastic TSOP I
HM514100AT/ALT/ASLT-7	70 ns	(TFP-20DA)
HM514100AT/ALT/ASLT-8	80 ns	
HM514100AT/ALT/ASLT-10	100 ns	
HM514100AR/ALR/ASLR-6	60 ns	20-pin Plastic TSOP I
HM514100AR/ALR/ASLR-7	70 ns	Reverse Type
HM514100AR/ALR/ASLR-8	80 ns	(TTP-20DAR)
HM514100AR/ALR/ASLR-10	100 ns	
HM514100ATT/ALTT/ASLTT-6	60 ns	20-pin Plastic TSOP II
HM514100ATT/ALTT/ASLTT-7	70 ns	(TTP-20D)
HM514100ATT/ALTT/ASLTT-8	80 ns	
HM514100ATT/ALTT/ASLTT-10	100 ns	
HM514100ARR/ALRR/ASLRR-6	60 ns	20-pin Plastic TSOP II
HM514100ARR/ALRR/ASLRR-7	70 ns	Reverse Type
HM514100ARR/ALRR/ASLRR-8	80 ns	(TTP-20DR)
HM514100ARR/ALRR/ASLRR-10	100 ns	

HM514100AJ Series

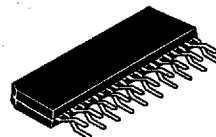
3DCP20DA

(CP-20DA)

HM514100AS Series

3DCP20D

(CP-20D)

HM514100AZ Series

3DZP20

(ZP-20)

HM514100AT Series

3DTFP20DA

(TFP-20DA)

HM514100AR Series

3DTFP20DAR

(TFP-20DAR)

HM514100ATT Series

3DTTP20D

(TTP-20D)

HM514100ARR Series

3DTTP20DR

(TTP-20DR)



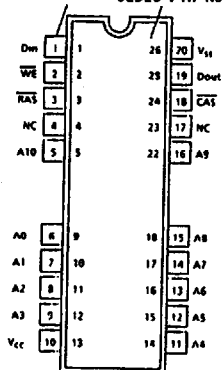
HM514100A Series

T-46-23-17

■ PIN OUT

HM514100AJ/ALJ/ASLJ Series
HM514100AS/ALS/ASLS Series

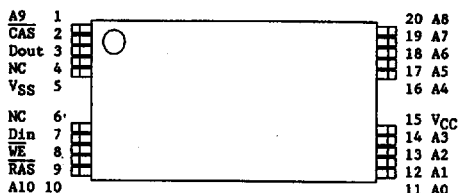
Hitachi Pin No. JEDEC Pin No.



(Top View)

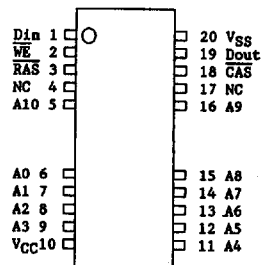
0091-1

HM514100AT/ALZ/ASLT Series



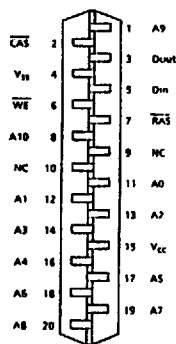
(Top View)

0091-3

HM514100ATT/ALTT
/ASLTT Series

(Top View)

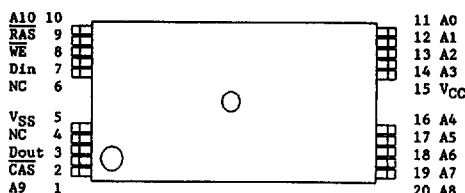
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HM514100AZ/ALZ/ASLZ
Series

(Bottom View)

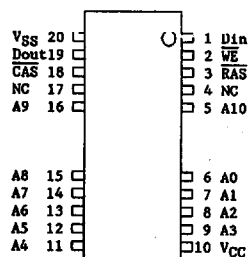
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HM514100AR/ALR/ASLR Series



(Top View)

0091-4

HM514100ARR/ALRR
/ASLRR Series

(Top View)

0091-6

■ PIN DESCRIPTION

Pin Name	Function
A ₀ -A ₁₀	Address Input
A ₀ -A ₉	Refresh Address Input
D _{in}	Data-in
D _{out}	Data-out
RAS	Row Address Strobe
CAS	Column Address Strobe
WE	Read/Write Enable
V _{CC}	Power (+ 5V)
V _{SS}	Ground
NC	No Connection



■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Voltage on Any Pin Relative to V_{SS}	V_T	-1.0 to +7.0	V
Supply Voltage Relative to V_{SS}	V_{CC}	-1.0 to +7.0	V
Short Circuit Output Current	I_{out}	50	mA
Power Dissipation	P_T	1.0	W
Operating Temperature	T_{opr}	0 to +70	°C
Storage Temperature	T_{stg}	-55 to +125	°C

T-46-23-17

■ ELECTRICAL CHARACTERISTICS

- Recommended DC Operating Conditions ($T_A = 0$ to +70°C)
($T_A = 0$ to +60°C (SL-Version))

Parameter	Symbol	Min	Typ	Max	Unit	Note
Supply Voltage	V_{SS}	0	0	0	V	
	V_{CC}	4.5	5.0	5.5	V	1
		4.0	—	5.5	V	1, 2 (SL-Version)
Input High Voltage	V_{IH}	2.4	—	6.5	V	1
Input Low Voltage	V_{IL}	-2.0	—	0.8	V	1

Notes: 1. All voltage referenced to V_{SS} .

2. Data retention operation only.

- DC Characteristics ($T_A = 0$ to +70°C, $V_{CC} = 5V \pm 10\%$, $V_{SS} = 0V$)
($T_A = 0$ to +60°C, $V_{CC} = 5V \pm 10\%$, $V_{SS} = 0V$ (SL-Version))

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Test Conditions	Note
		Min	Max	Min	Max	Min	Max	Min	Max			
Operating Current	I_{CC1}	—	110	—	100	—	90	—	80	mA	RAS, CAS Cycling $t_{RC} = \text{Min}$	1, 2
Standby Current	I_{CC2}	—	2	—	2	—	2	—	2	mA	TTL Interface RAS, CAS = V_{IH} $D_{out} = \text{High-Z}$	
		—	1	—	1	—	1	—	1	mA	CMOS Interface RAS, CAS > $V_{CC} - 0.2V$ $D_{out} = \text{High-Z}$	
[L-Version] Standby Current		—	200	—	200	—	200	—	200	μA	CMOS Interface RAS, CAS = V_{IH} WE, Address and $D_{in} = V_{IH}$ or V_{IL} $D_{out} = \text{High-Z}$	4
[SL-Version] Standby Current		—	100	—	100	—	100	—	100	μA	CMOS Interface RAS, CAS = V_{IH} WE, Address and $D_{in} = V_{IH}$ or V_{IL} $D_{out} = \text{High-Z}$	4
RAS Only Refresh Current	I_{CC3}	—	110	—	100	—	90	—	80	mA	$t_{RC} = \text{Min}$	2
Standby Current	I_{CC5}	—	5	—	5	—	5	—	5	mA	RAS = V_{IH} CAS = V_{IL} $D_{out} = \text{Enable}$	1
CAS Before RAS Refresh Current	I_{CC6}	—	110	—	100	—	90	—	80	mA	$t_{RC} = \text{Min}$	
Fast Page Mode Current	I_{CC7}	—	110	—	100	—	90	—	80	mA	$t_{PC} = \text{Min}$	1, 3



HM514100A Series

- **DC Characteristics** ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, $V_{SS} = 0\text{V}$)
 ($T_A = 0$ to $+60^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, $V_{SS} = 0\text{V}$ (SL-Version)) (continued)

T-46-23-17

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Test Conditions	Note
		Min	Max	Min	Max	Min	Max	Min	Max			
[L-Version] Battery Back Up Operating Current (Standby with CBR Refresh)	I _{CC10}	—	300	—	300	—	300	—	300	μA	$t_{RC} = 125\ \mu\text{s}$ $t_{RAS} \leq 1\ \mu\text{s}$ $WE = V_{IH}$ $CAS = V_{IL}$ Address, $D_{in} = V_{IH}$ or V_{IL} $D_{out} = \text{High-Z}$	4
[SL-Version] Data Retention Current (Equivalent Refresh Time is 256 ms)		—	150	—	150	—	150	—	150	μA	$t_{RC} = 250\ \mu\text{s}$ $t_{RAS} \leq 200\ \text{ns}$ $WE = V_{IH}$ $CAS = V_{IL}$ Address, $D_{in} = V_{IH}$ or V_{IL} $D_{out} = \text{High-Z}$ $4.0\text{V} \leq V_{CC} \leq 5.5\text{V}$	4
Input Leakage Current	I _{LI}	-10	10	-10	10	-10	10	-10	10	μA	$0\text{V} \leq V_{IN} \leq 7\text{V}$	
Output Leakage Current	I _{LO}	-10	10	-10	10	-10	10	-10	10	μA	$0\text{V} \leq V_{IN} \leq 7\text{V}$ $D_{out} = \text{Disable}$	
Output High Voltage	V _{OH}	2.4	V _{CC}	2.4	V _{CC}	2.4	V _{CC}	2.4	V _{CC}	V	High I _{out} = -5 mA	
Output Low Voltage	V _{OL}	0	0.4	0	0.4	0	0.4	0	0.4	V	Low I _{out} = 4.2 mA	

Notes: 1. I_{CC} depends on output load condition when the device is selected, I_{CC} max is specified at the output open condition.

2. Address can be changed once or less while $\overline{RAS} = V_{IL}$.

3. Address can be changed once or less while $\overline{CAS} = V_{IH}$.

4. $V_{CC} - 0.2\text{V} \leq V_{IH} \leq 6.5\text{V}$ and $0\text{V} \leq V_{IL} \leq 0.2\text{V}$.

- **Capacitance** ($T_A = 25^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$)

Parameter	Symbol	Typ	Max	Unit	Note
Input Capacitance (Address, Data-in)	C _{I1}	—	5	pF	1
Input Capacitance (Clocks)	C _{I2}	—	7	pF	1
Output Capacitance (Data-out)	C _O	—	7	pF	1, 2

Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.

2. $\overline{CAS} = V_{IH}$ to disable D_{out}.

- **AC Characteristics** ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, $V_{SS} = 0\text{V}$)^{1, 12, 15}
 ($T_A = 0$ to $+60^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, $V_{SS} = 0\text{V}$ (SL-Version))

Test Conditions: Input rise and fall times: 5 ns

Input timing reference levels: 0.8V, 2.4V

Output load: 2 TTL Gate + CL (100 pF) (Including scope and jig)

Read, Write, Read-Modify-Write and Refresh Cycles (Common Parameters)

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
Random Read or Write Cycle Time	t _{RC}	110	—	130	—	150	—	180	—	ns	
RAS Precharge Time	t _{RP}	40	—	50	—	60	—	70	—	ns	
RAS Pulse Width	t _{RAS}	60	10000	70	10000	80	10000	100	10000	ns	
CAS Pulse Width	t _{CAS}	15	10000	20	10000	20	10000	25	10000	ns	
Row Address Setup Time	t _{ASR}	0	—	0	—	0	—	0	—	ns	
Row Address Hold Time	t _{RAH}	10	—	10	—	10	—	15	—	ns	



Read, Write, Read-Modify-Write and Refresh Cycles (Common Parameters) (continued)

T-46-23-17

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
Column Address Setup Time	t _{ASC}	0	—	0	—	0	—	0	—	ns	
Column Address Hold Time	t _{CAH}	15	—	15	—	15	—	20	—	ns	
RAS to CAS Delay Time	t _{RCD}	20	45	20	50	20	60	25	75	ns	8
RAS to Column Address Delay Time	t _{RAD}	15	30	15	35	15	40	20	55	ns	9
RAS Hold Time	t _{RSH}	15	—	20	—	20	—	25	—	ns	
CAS Hold Time	t _{CSH}	60	—	70	—	80	—	100	—	ns	
CAS to RAS Precharge Time	t _{CRP}	10	—	10	—	10	—	10	—	ns	
Transition Time (Rise and Fall)	t _T	3	50	3	50	3	50	3	50	ns	7
Refresh Period	t _{REF}	—	16	—	16	—	16	—	16	ms	
Refresh Period (L-Version)	t _{REF}	—	128	—	128	—	128	—	128	ms	
Refresh Period (SL-Version)	t _{REF}	—	16	—	16	—	16	—	16	ms	

Read Cycle

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
Access Time from RAS	t _{RAC}	—	60	—	70	—	80	—	100	ns	2, 3, 16
Access Time from CAS	t _{CAC}	—	15	—	20	—	20	—	25	ns	3, 4, 14, 16
Access Time from Address	t _{AA}	—	30	—	35	—	40	—	45	ns	3, 5, 14, 16
Read Command Setup Time	t _{RCS}	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to CAS	t _{RCH}	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to RAS	t _{RRH}	0	—	0	—	0	—	0	—	ns	
Column Address to RAS Lead Time	t _{RAL}	30	—	35	—	40	—	45	—	ns	
Output Buffer Turn-off Time	t _{OFF}	0	15	0	20	0	20	0	25	ns	6

Write Cycle

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
Write Command Setup Time	t _{WCS}	0	—	0	—	0	—	0	—	ns	10
Write Command Hold Time	t _{WCH}	15	—	15	—	15	—	20	—	ns	
Write Command Pulse Width	t _{WP}	10	—	10	—	10	—	20	—	ns	
Write Command to RAS Lead Time	t _{RWL}	15	—	20	—	20	—	25	—	ns	
Write Command to CAS Lead Time	t _{CWL}	15	—	20	—	20	—	25	—	ns	
Data-in Setup Time	t _{DS}	0	—	0	—	0	—	0	—	ns	11
Data-in Hold Time	t _{DH}	15	—	15	—	15	—	20	—	ns	11

Read-Modify-Write Cycle

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
Read-Modify-Write Cycle Time	t _{RWC}	130	—	155	—	175	—	210	—	ns	
RAS to $\overline{\text{WE}}$ Delay Time	t _{RWD}	60	—	70	—	80	—	100	—	ns	10
CAS to $\overline{\text{WE}}$ Delay Time	t _{CWD}	15	—	20	—	20	—	25	—	ns	10
Column Address to $\overline{\text{WE}}$ Delay Time	t _{AWD}	30	—	35	—	40	—	45	—	ns	10

Refresh Cycle

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
CAS Setup Time (CAS Before RAS Refresh Cycle)	t _{CSR}	10	—	10	—	10	—	10	—	ns	
CAS Hold Time (CAS Before RAS Refresh Cycle)	t _{CHR}	10	—	10	—	10	—	10	—	ns	
RAS Precharge to CAS Hold Time	t _{RPC}	10	—	10	—	10	—	10	—	ns	
CAS Precharge Time in Normal Mode	t _{CPN}	10	—	10	—	10	—	10	—	ns	

Fast Page Mode Cycle

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
Fast Page Mode Cycle Time	t _{PC}	40	—	45	—	50	—	55	—	ns	
Fast Page Mode CAS Precharge Time	t _{CP}	10	—	10	—	10	—	10	—	ns	
Fast Page Mode RAS Pulse Width	t _{RASC}	—	100000	—	100000	—	100000	—	100000	ns	13
Access Time from CAS Precharge	t _{ACP}	—	35	—	40	—	45	—	50	ns	3, 14, 16
RAS Hold Time from CAS Precharge	t _{RHCP}	35	—	40	—	45	—	50	—	ns	

Fast Page Mode Read-Modify-Write Cycle

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
Fast Page Mode Read-Modify-Write Cycle Time	t _{PCM}	60	—	70	—	75	—	85	—	ns	
CAS Precharge to $\overline{\text{WE}}$ Delay Time	t _{CPW}	35	—	40	—	45	—	50	—	ns	10

Test Mode Cycle

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
Test Mode $\overline{\text{WE}}$ Setup Time	t _{WS}	0	—	0	—	0	—	0	—	ns	
Test Mode $\overline{\text{WE}}$ Hold Time	t _{WH}	10	—	10	—	10	—	10	—	ns	

Counter Test Cycle

Parameter	Symbol	HM514100A-6		HM514100A-7		HM514100A-8		HM514100A-10		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max		
CAS Precharge Time in Counter Test Cycle	t _{CPT}	40	—	40	—	40	—	40	—	ns	



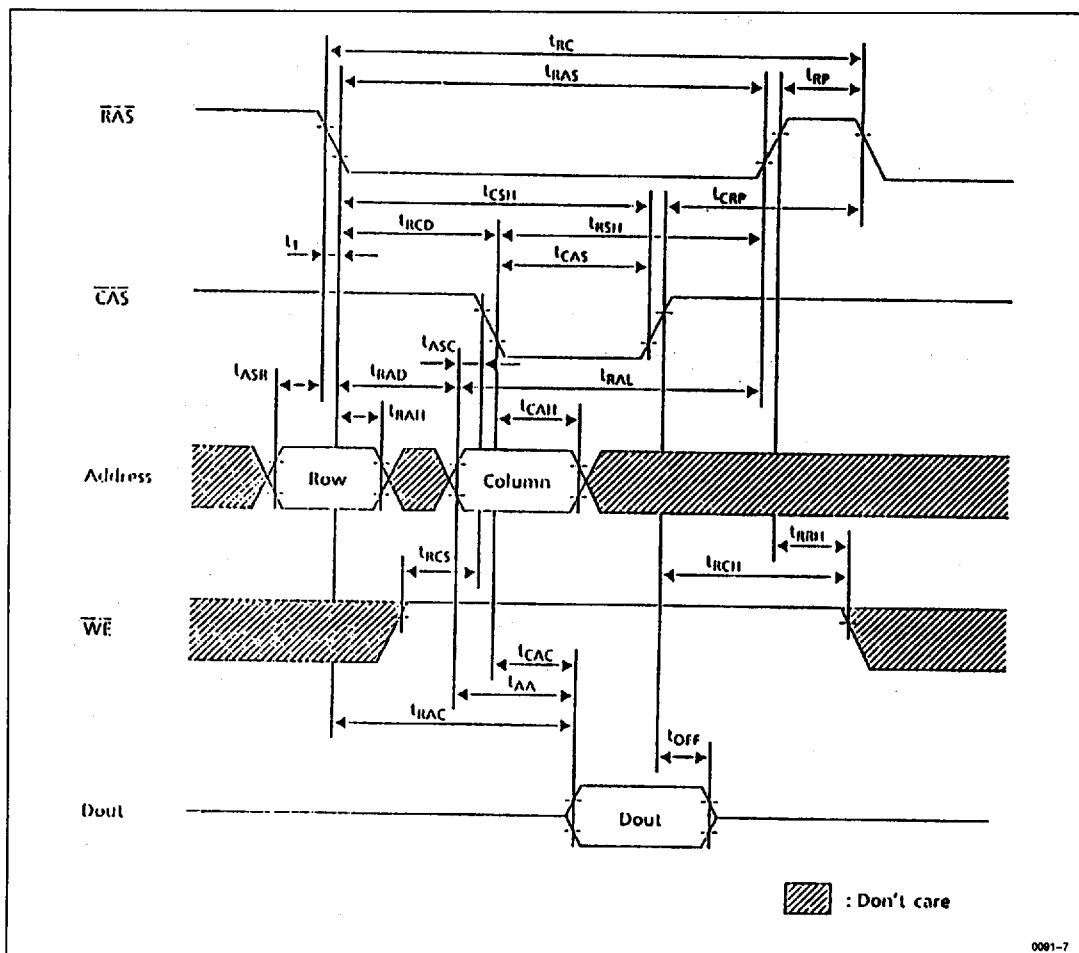
Notes: 1. AC measurements assume $t_T = 5$ ns.

2. Assumes that $t_{RCD} \leq t_{RCD}(\max)$ and $t_{RAD} \leq t_{RAD}(\max)$. If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} exceeds the value shown.
3. Measured with a load circuit equivalent to 2 TTL loads and 100 pF.
4. Assumes that $t_{RCD} \geq t_{RCD}(\max)$ and $t_{RAD} \leq t_{RAD}(\max)$.
5. Assumes that $t_{RCD} \leq t_{RCD}(\max)$ and $t_{RAD} \geq t_{RAD}(\max)$.
6. $t_{OFF}(\max)$ defines the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
7. $V_{IH}(\min)$ and $V_{IL}(\max)$ are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
8. Operation with the $t_{RCD}(\max)$ limit insures that $t_{RAC}(\max)$ can be met, $t_{RCD}(\max)$ is specified as a reference point only, if t_{RCD} is greater than the specified $t_{RCD}(\max)$ limit, then access time is controlled exclusively by t_{CAC} .
9. Operation with the $t_{RAD}(\max)$ limit insures that $t_{RAC}(\max)$ can be met, $t_{RAD}(\max)$ is specified as a reference point only, if t_{RAD} is greater than the specified $t_{RAD}(\max)$ limit, then access time is controlled exclusively by t_{AA} .
10. t_{WCS} , t_{RWD} , t_{CWD} , t_{AWD} and t_{CPW} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only: if $t_{WCS} \geq t_{WCS}(\min)$, the cycle is an early write cycle and the data out pin will remain open circuit (high impedance) throughout the entire cycle; if $t_{RWD} \geq t_{RWD}(\min)$, $t_{CWD} \geq t_{CWD}(\min)$, $t_{AWD} \geq t_{AWD}(\min)$ and $t_{CPW} \geq t_{CPW}(\min)$, the cycle is a read-modify-write and the data output will contain data read from the selected cell; if neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.
11. These parameters are referenced to $\overline{CAS}$ leading edge in an early write cycle and to $\overline{WE}$ leading edge in a delayed write or a read-modify-write cycle.
12. An initial pause of 100 μ s is required after power up followed by a minimum of eight initialization cycles ($\overline{RAS}$ only refresh cycle or $\overline{CAS}$ before $\overline{RAS}$ refresh cycle). If the internal refresh counter is used, a minimum of eight $\overline{CAS}$ before $\overline{RAS}$ refresh cycles is required.
13. t_{RASC} defines $\overline{RAS}$ pulse width in fast page mode cycles.
14. Access time is determined by the longer of t_{AA} or t_{CAC} or t_{ACP} .
15. Test mode operation specified in this data sheet is 8-bit test function controlled by control address bits— RA_{10} , CA_{10} and CA_0 . This test mode operation can be performed by $\overline{WE}$ and $\overline{CAS}$ before $\overline{RAS}$ (WCBR) refresh cycle. Refresh during test mode operation will be performed by normal read cycles or by WCBR refresh cycles. When the state of eight test bits accord each other, the condition of the output data is high level. When the state of test bits do not accord, the condition of the output data is low level. Data output pin is D_{out} and data input pin is D_{in} . In order to end this test mode operation, perform a $\overline{RAS}$ only refresh cycle or a $\overline{CAS}$ before $\overline{RAS}$ refresh cycle.
16. In a test mode read cycle, the value of t_{RAC} , t_{AA} , t_{CAC} and t_{ACP} is delayed for 2 ns to 5 ns for the specified value. These parameters should be specified in test mode cycles by adding the above value to the specified value in this data sheet.



■ TIMING WAVEFORMS

• Read Cycle



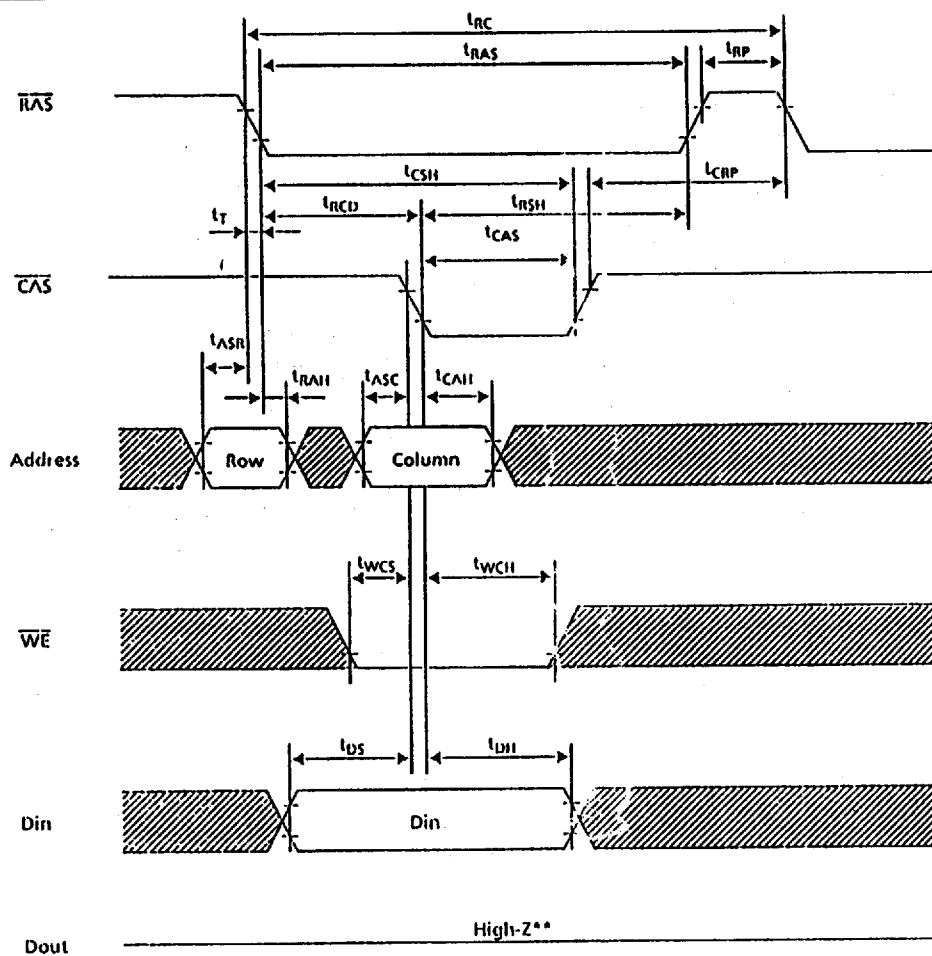
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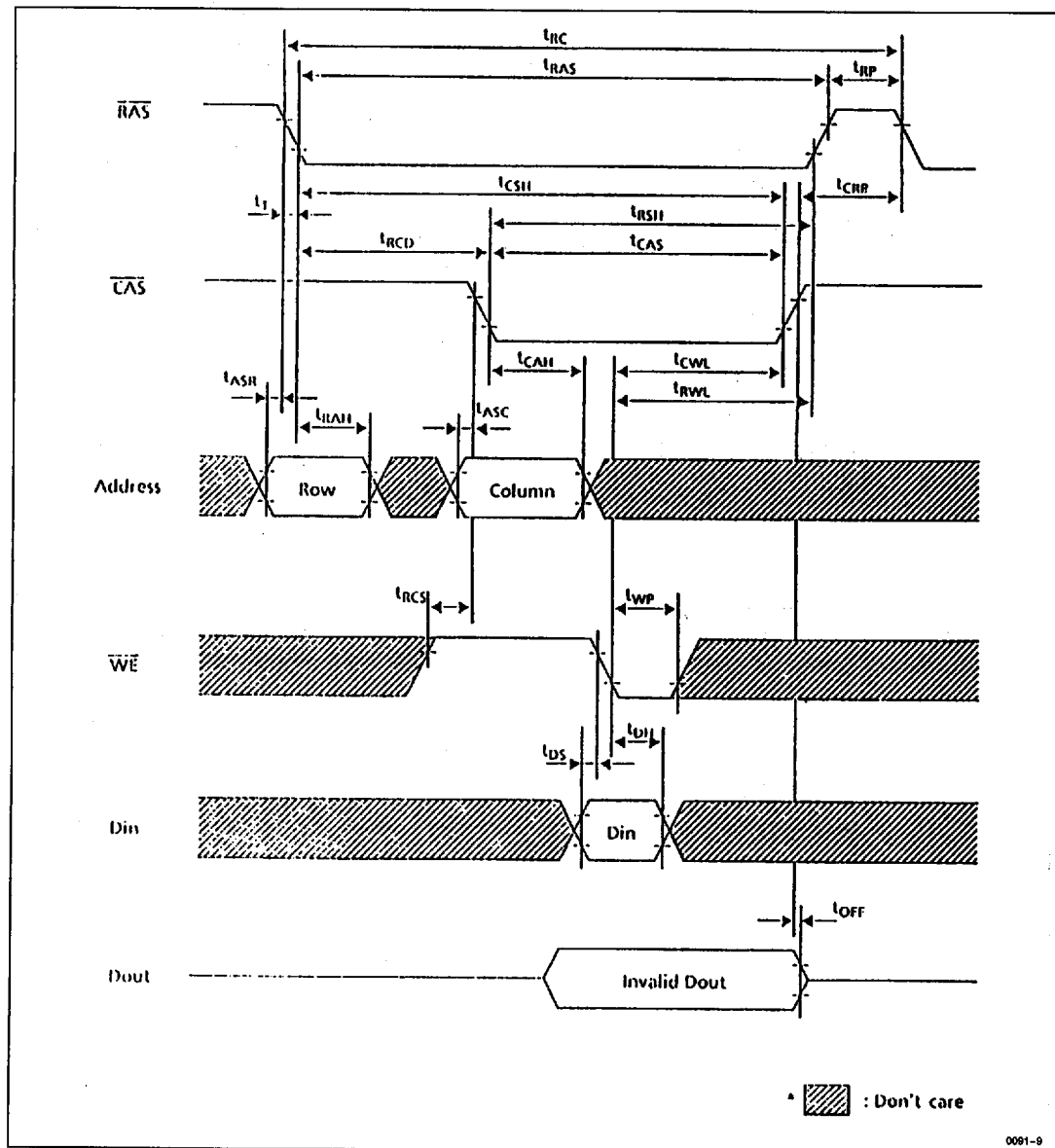
• Early Write Cycle

T-46-23-17



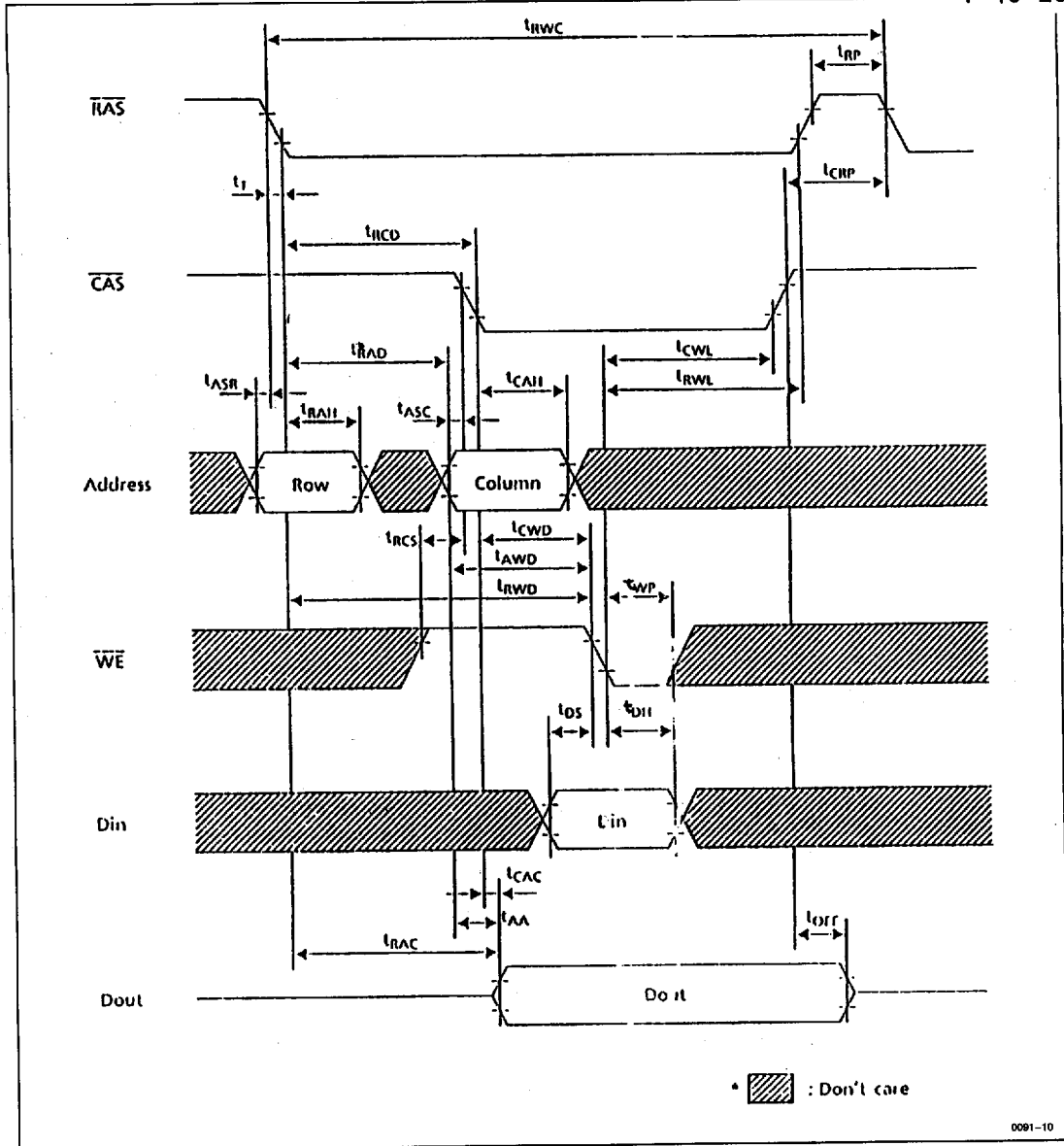
0091-8





• Read-Modify-Write Cycle

T-46-23-17

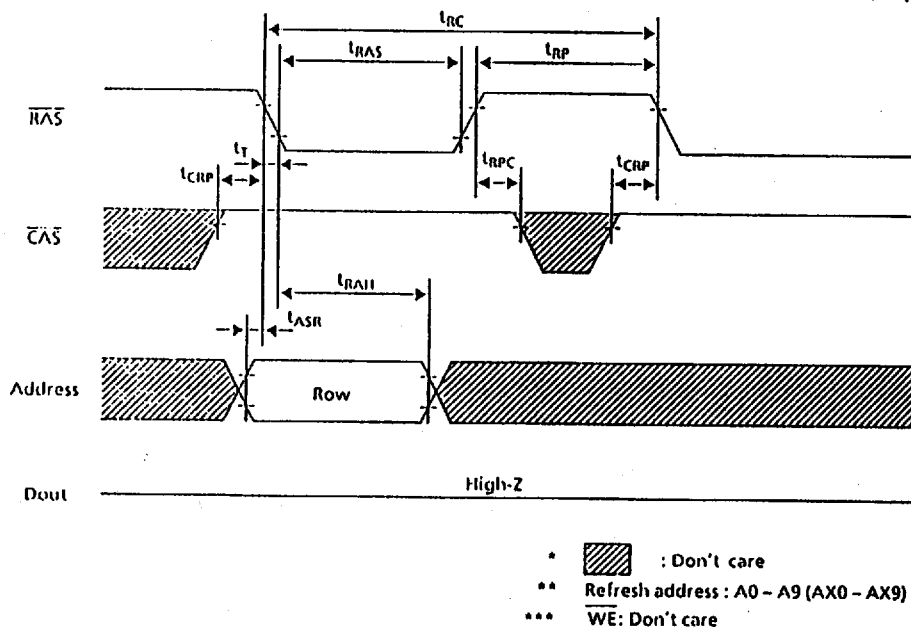


0091-10



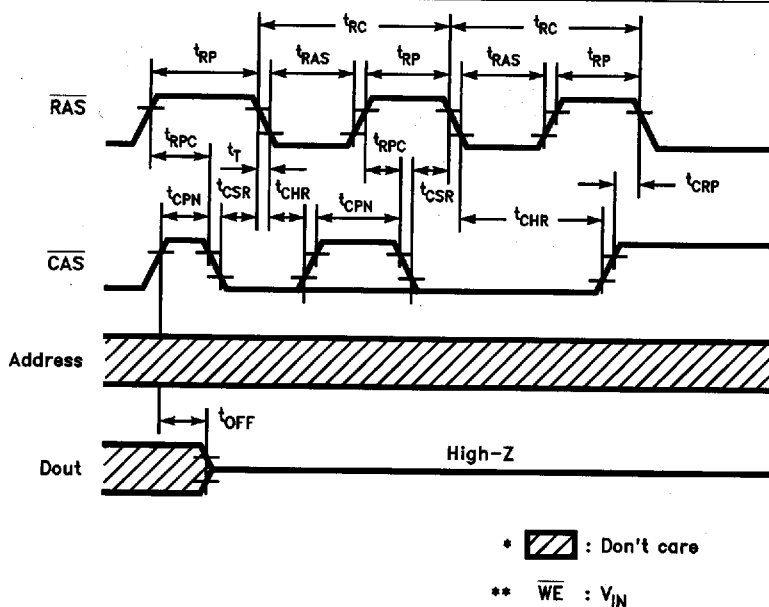
• RAS Only Refresh Cycle

T-46-23-17



0091-11

• CAS Before RAS Refresh Cycle

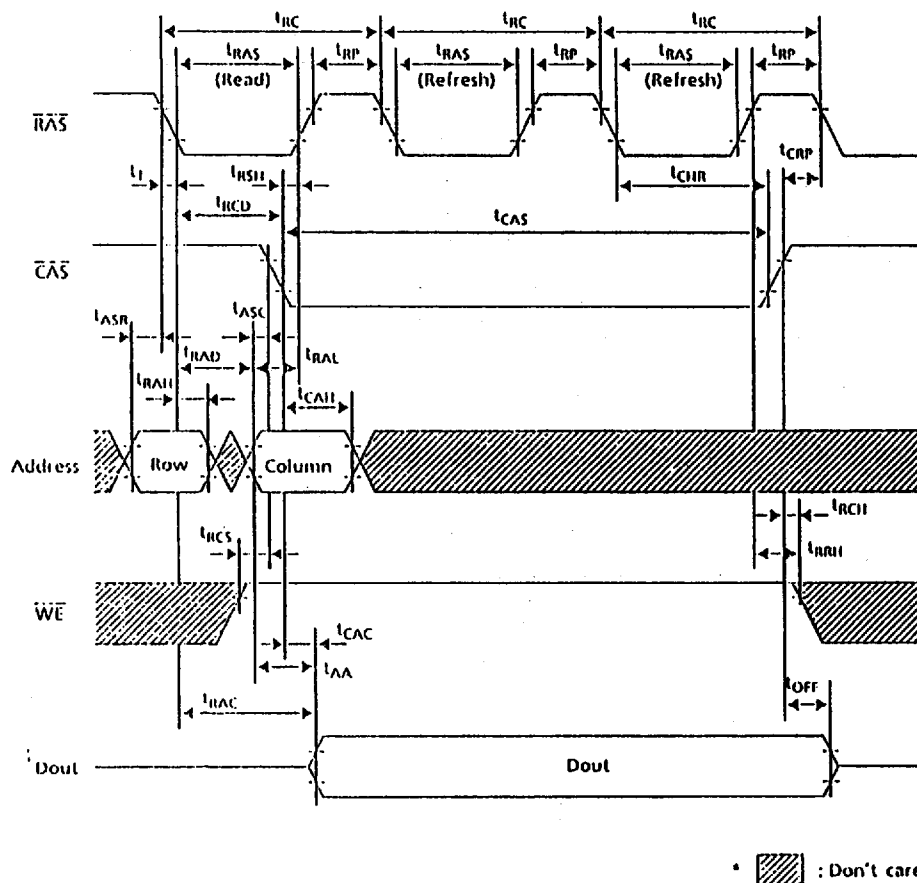


0091-12



• Hidden Refresh Cycle

T-46-23-17

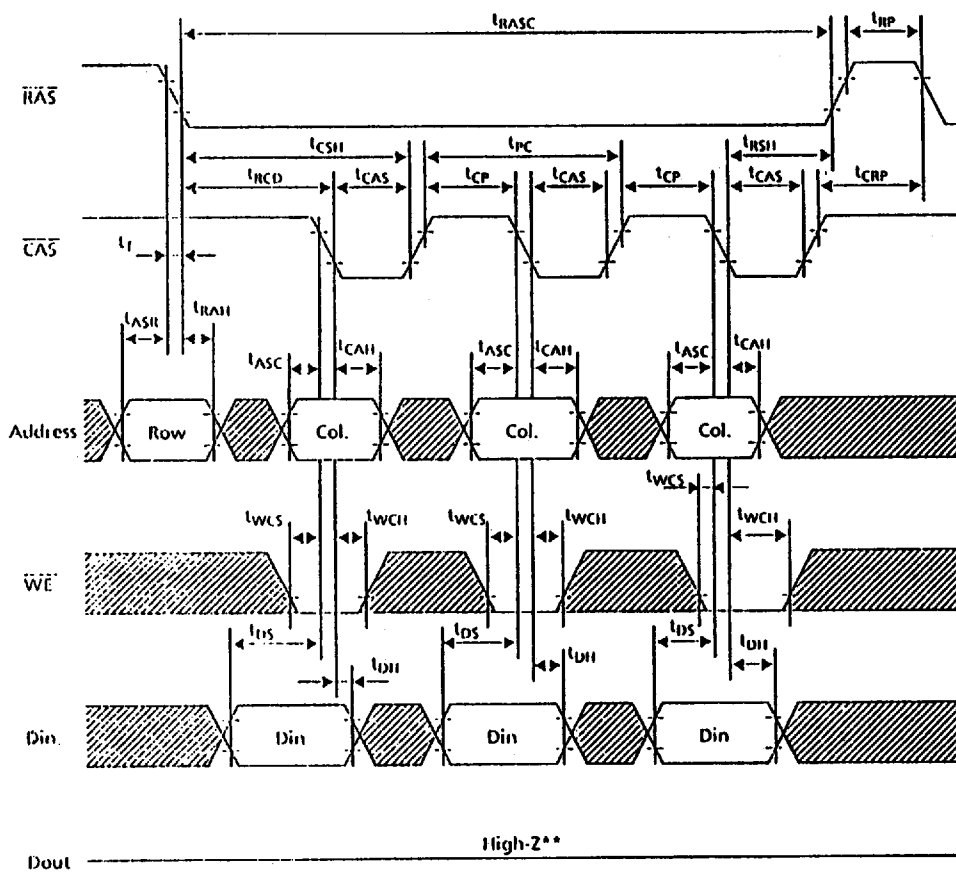


0091-13



• Fast Page Mode Early Write Cycle

T-46-23-17

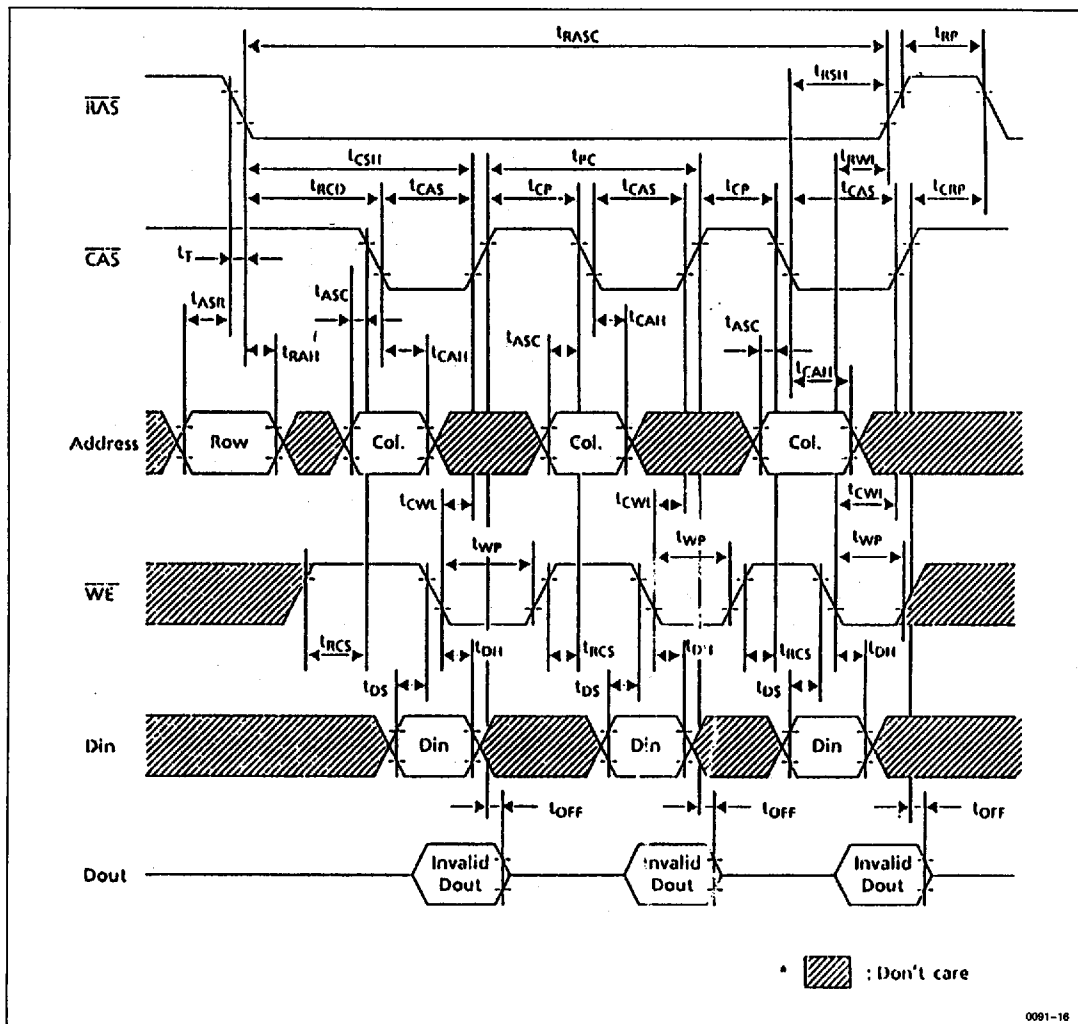


• : Don't care

** $t_{WCS} \geq t_{WCS}(\text{min})$

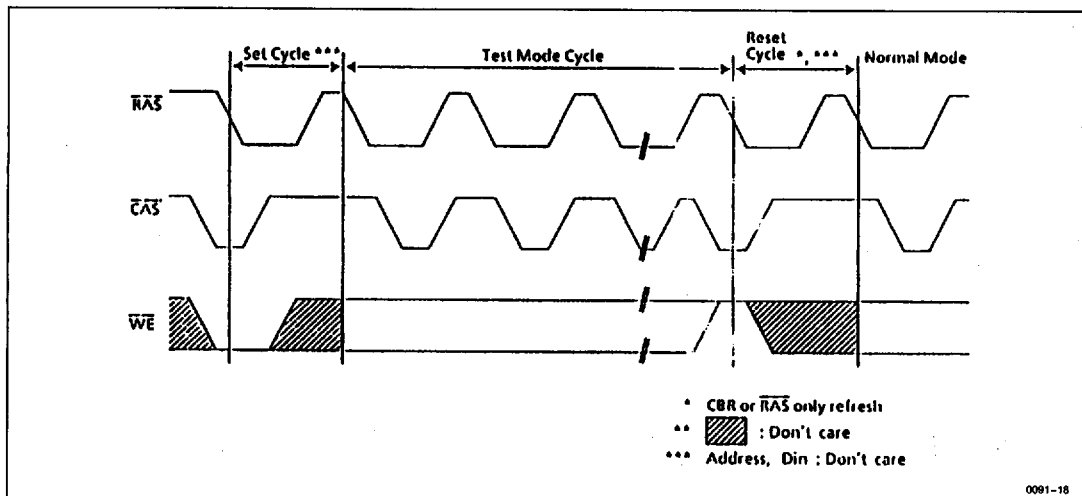
0091-15



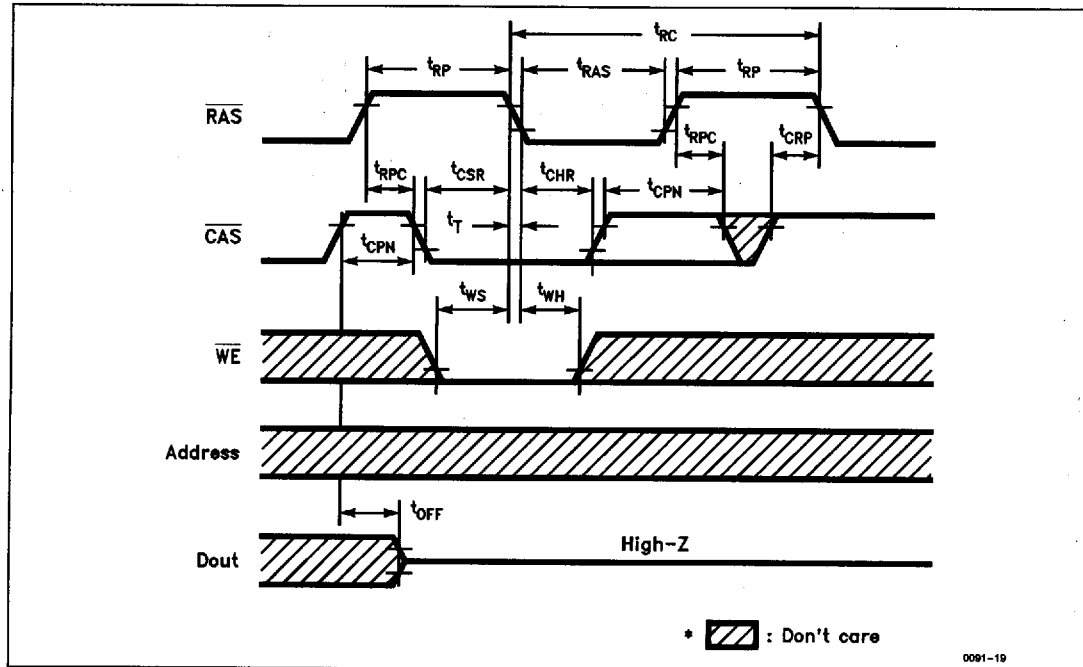


T-46-23-17



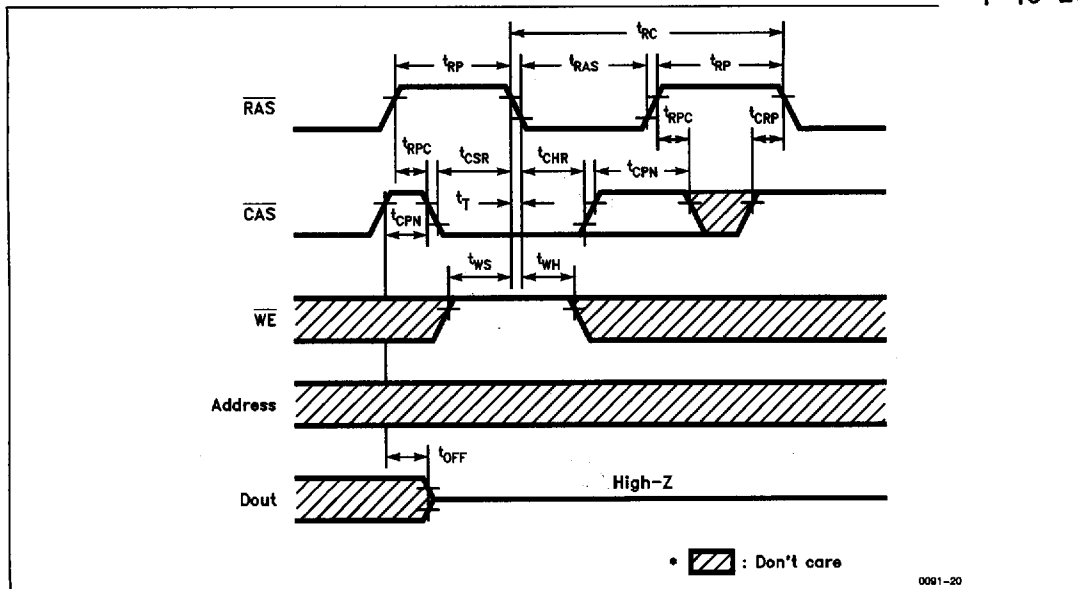


• Test Mode Set Cycle

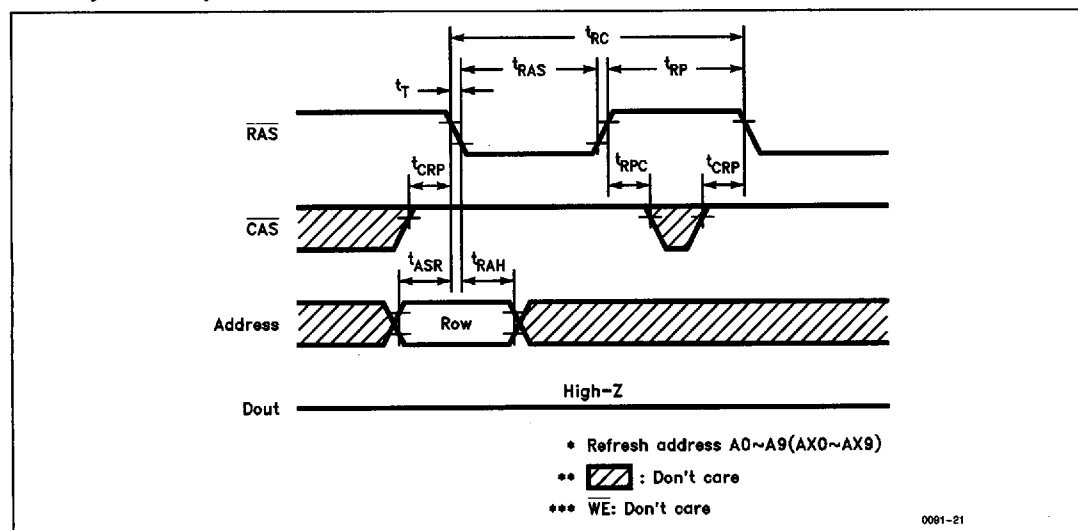
WE And $\overline{CAS}$ Before RAS Refresh

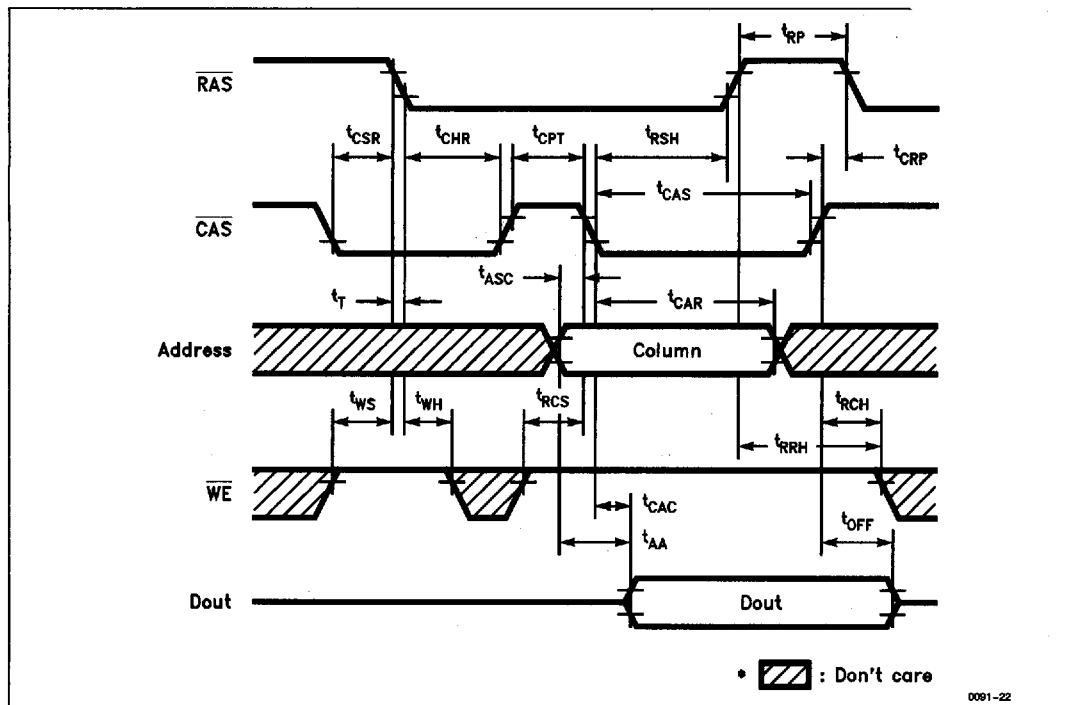
• Test Mode Reset Cycle
CAS Before RAS Refresh Cycle

T-46-23-17



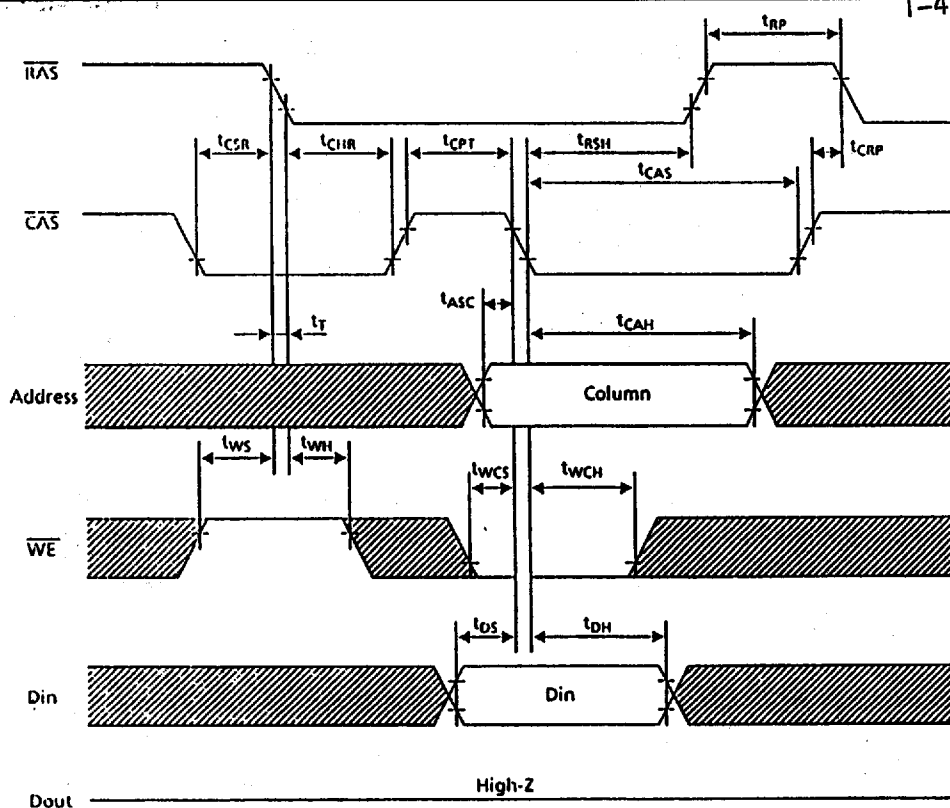
RAS Only Refresh Cycle





• $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Counter Check Cycle (Write)

T-46-23-17



* : Don't care

0081-28

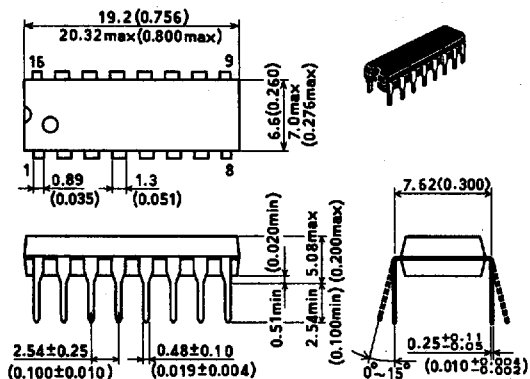


T-90-20

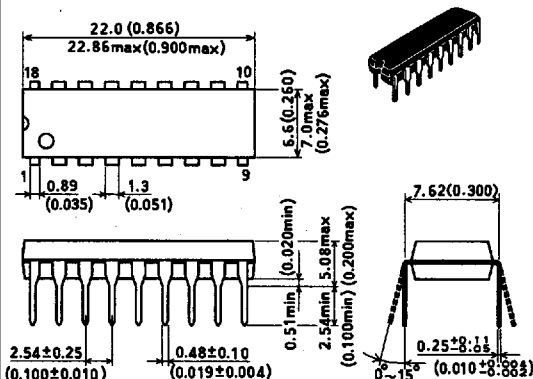
Unit: mm (inch) Scale 3/2

• Dual-in-line Plastic

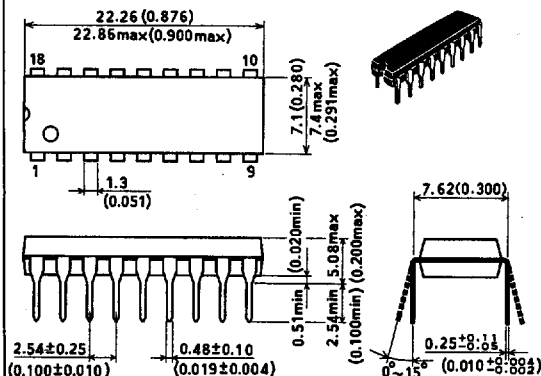
• DP-16B



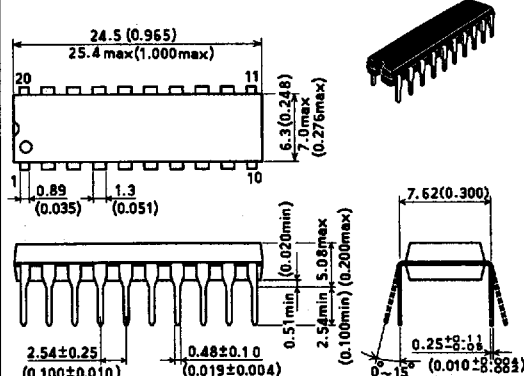
• DP-18B



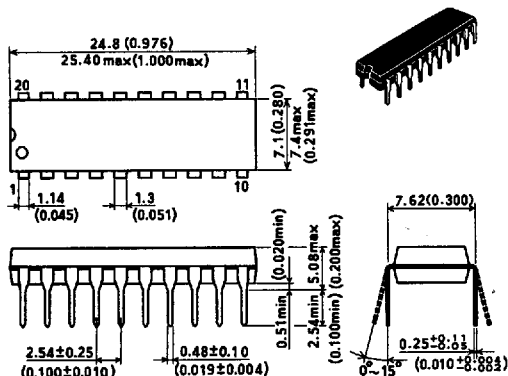
• DP-18C



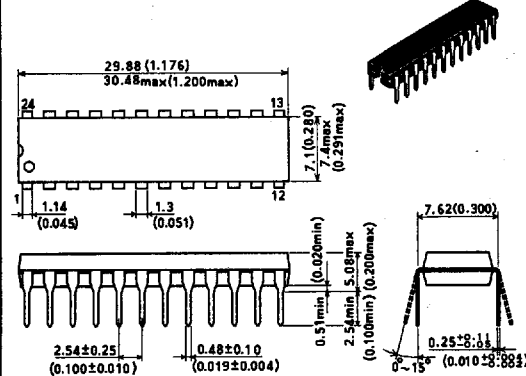
• DP-20N



• DP-20NA



• DP-20NC

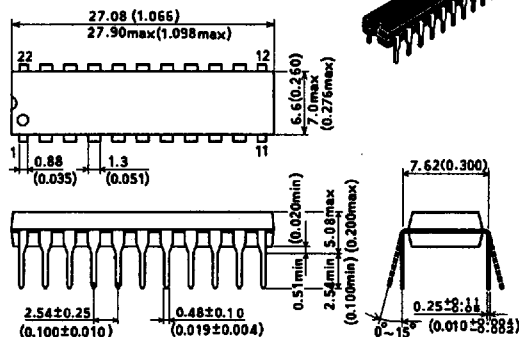


• Dual-In-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

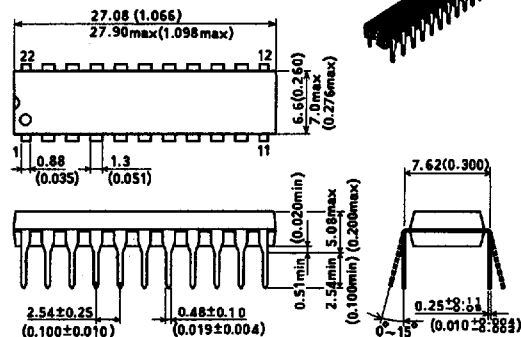
Unit: mm (inch) Scale 3/2

• DP-22N

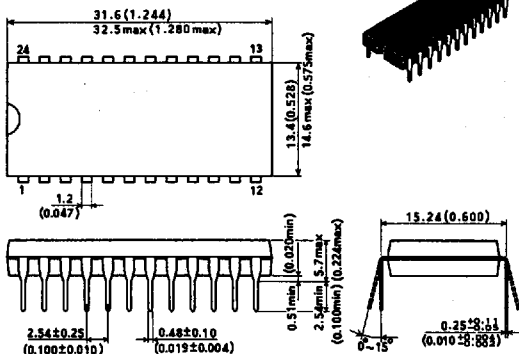


• DP-22NB

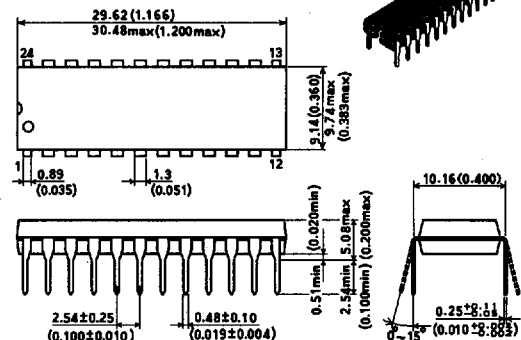
T-90-20



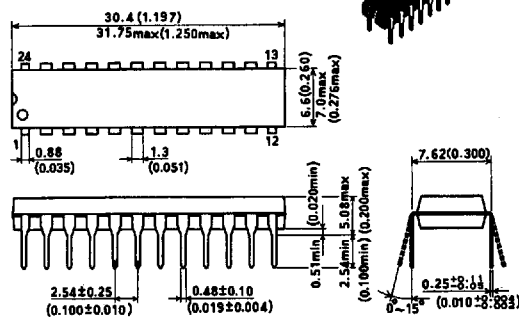
• DP-24



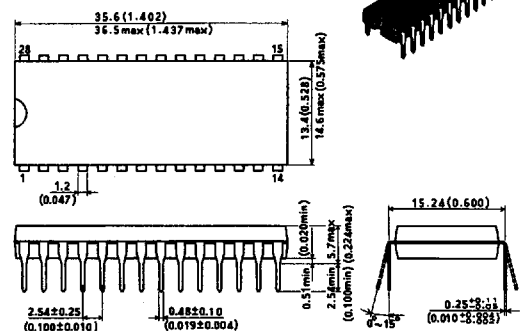
• DP-24A



• DP-24N



• DP-28

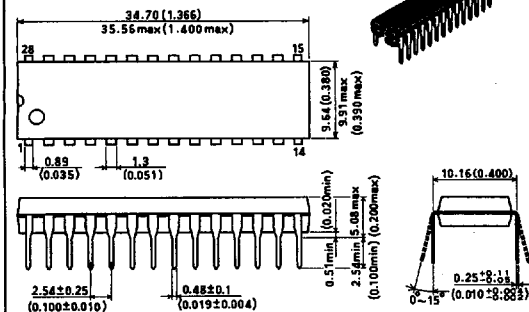


• Dual-in-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

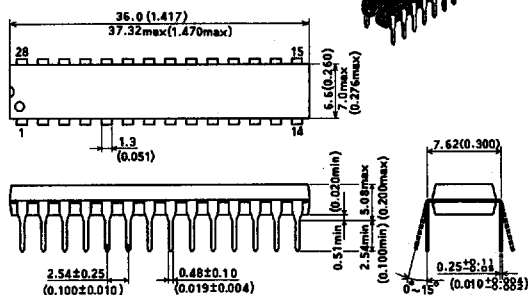
Unit: mm (inch) Scale 3/2

• DP-28C

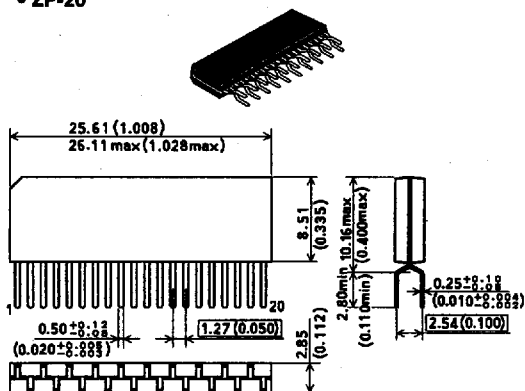


• DP-28N

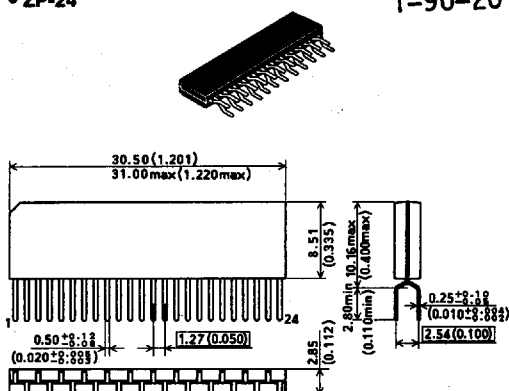
T-90-20



• ZP-20

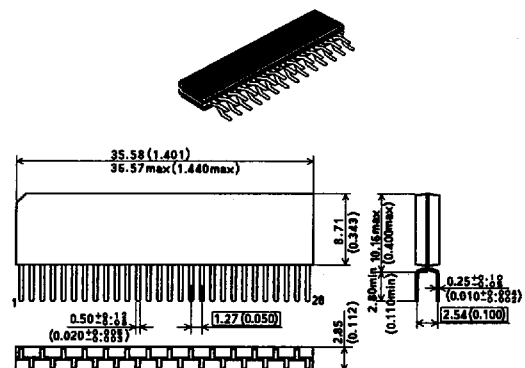


• ZP-24

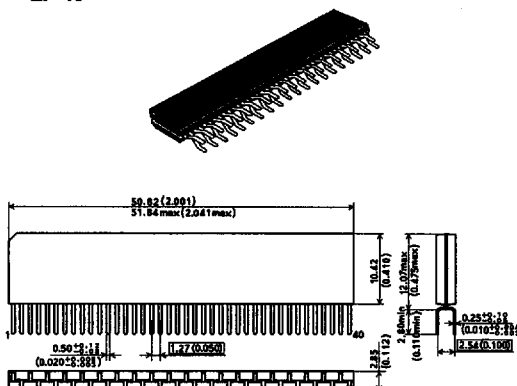


T-90-20

• ZP-28



• ZP-40



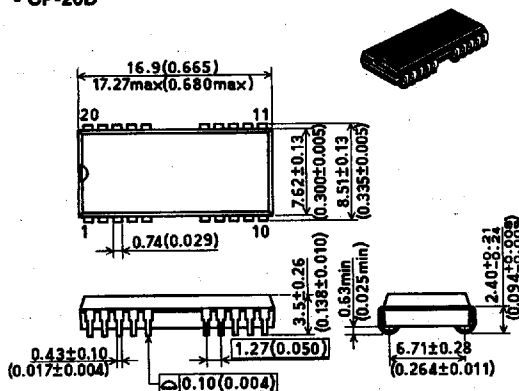
• Flat Package (J-bend Leads)

HITACHI/ LOGIC/ARRAYS/MEM

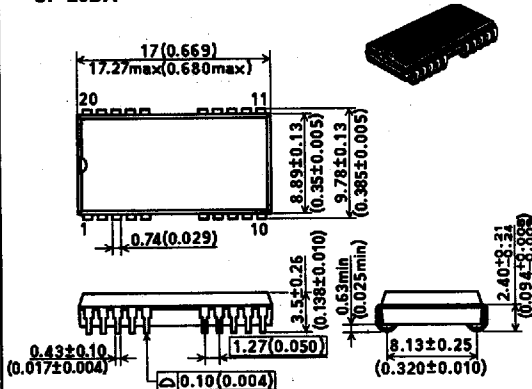
Unit: mm (inch) Scale 3/2

T-90-20

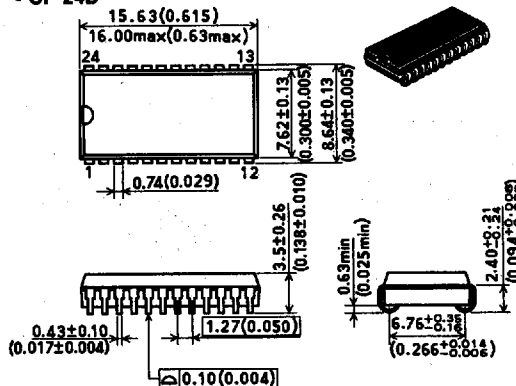
• CP-20D



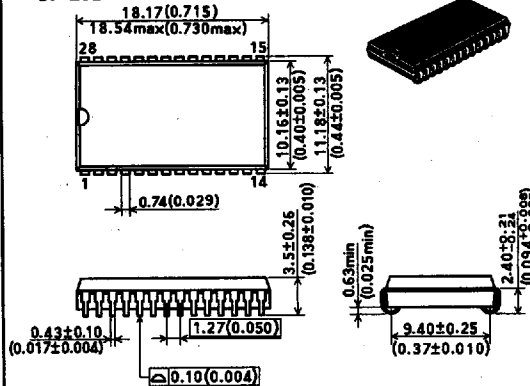
• CP-20DA



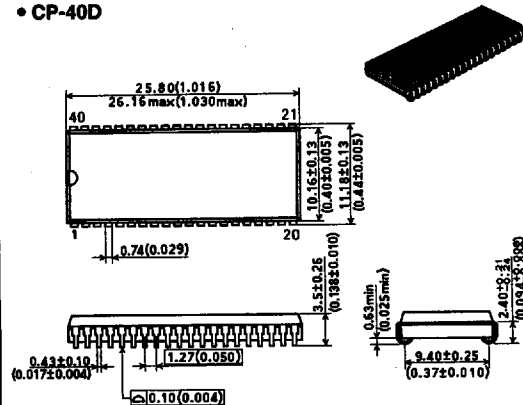
• CP-24D



• CP-28D



• CP-40D

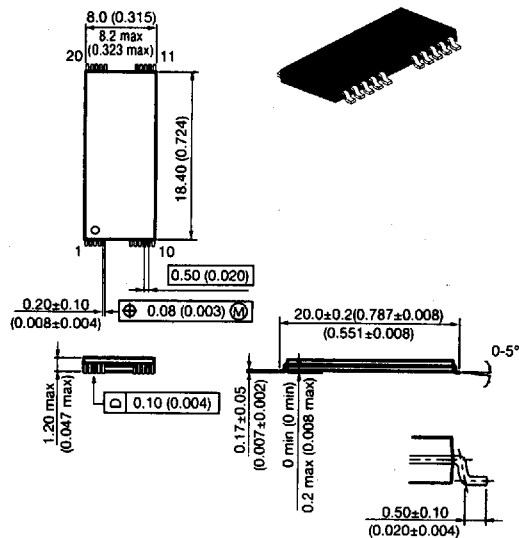


• TSOP (Thin Small Outline Package)

HITACHI/ LOGIC/ARRAYS/MEM

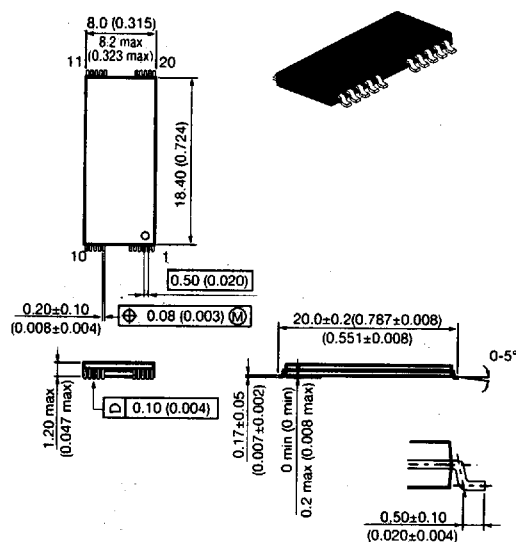
Unit: mm (inch) Scale 3/2

• TFP-20DA

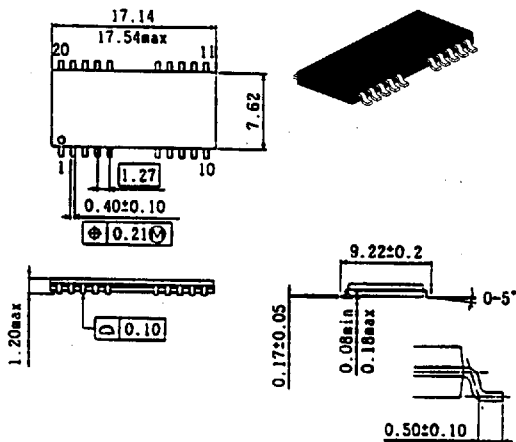


• TFP-20DAR

T-90-20



• TTP-20D



• TTP-20DR

